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(54) STRAIGHT PROTRUDING PROBE BEAM CONTOUR SURFACES

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(US)

(**) Term: 14 Years

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Related U.S. Application Data

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(52) U.S. Cl. D10/78

324/537, 750–762

(56) References Cited

U.S. PATENT DOCUMENTS

6,515,496 B2 *	2/2003	Felici et al 324/754
6,530,148 B1 *	3/2003	Kister 324/754
2003/0057957 A1	3/2003	McQuade et al 324/537

^{*} cited by examiner

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(57) CLAIM

The ornamental design for straight protruding probe beam contour surfaces, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of an exemplary environmental structure of a probe beam having straight protruding probe beam contour surfaces.

FIG. 2 is a plan view of an exemplary environmental structure of a probe beam in protruding direction of the straight protruding probe beam contour surfaces. Section lines indicate the position of the corresponding cross sec-

tions of FIGS. 8, 9, 10 with respect to the exemplary environmental structure of a probe beam. The section line arrows on both ends of each section line indicate the view direction of the corresponding cross section views.

FIG. 3 is a plan view of an exemplary environmental structure of a probe beam in protruding direction of the straight protruding probe beam contour surfaces without section lines.

FIG. 4 is a top view in direction from above with respect to FIG. 3. The solid lines depict the straight protruding probe beam contour surfaces. The dashed lines illustrate the environmental structure of an exemplary buckling beam.

FIG. 5 is a side view in direction from right with respect to FIG. 3. The solid lines depict the straight protruding probe beam contour surfaces. The dashed lines illustrate the environmental structure of an exemplary buckling beam.

FIG. 6 is a bottom view in direction from below with respect to FIG. 3. The solid lines depict the straight protruding probe beam contour surfaces. The dashed lines illustrate the environmental structure of an exemplary buckling beam.

FIG. 7 is a side view in direction from left with respect to FIG. 3. The solid lines depict the straight protruding probe beam contour surfaces. The dashed lines illustrate the environmental structure of an exemplary buckling beam.

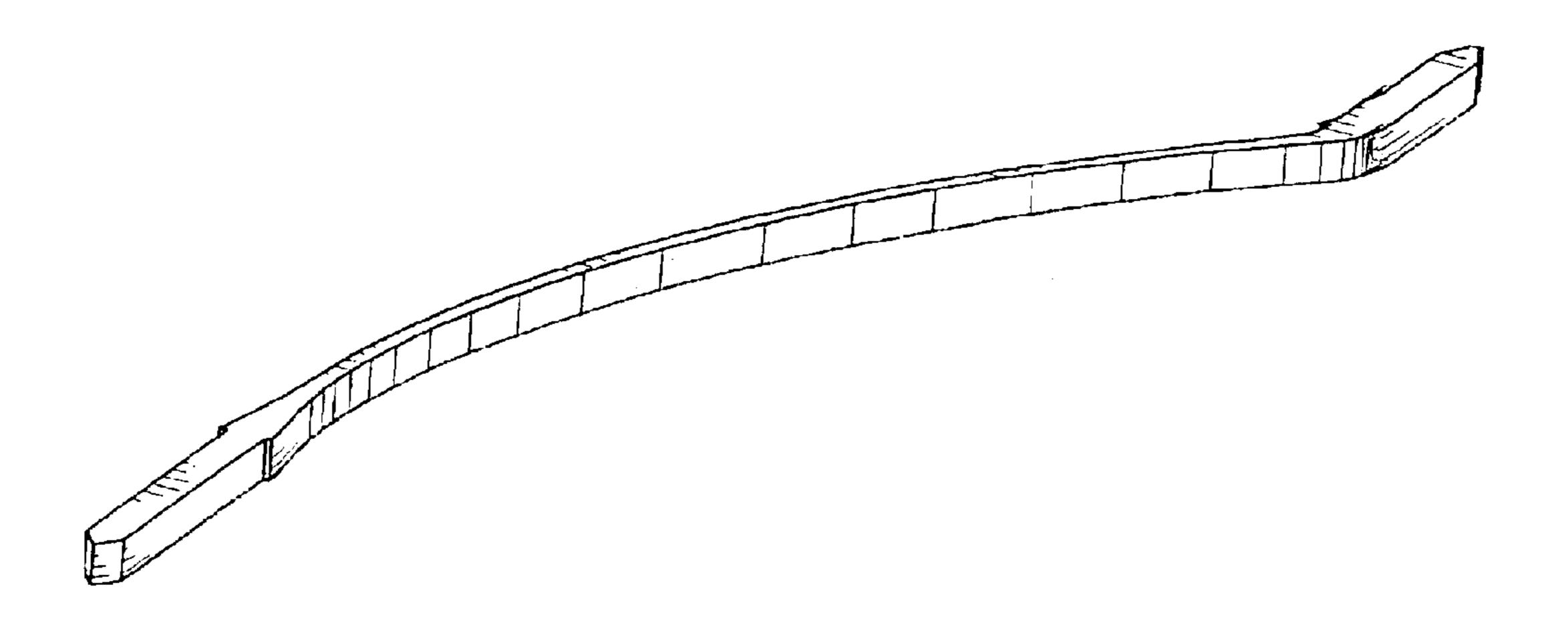
FIG. 8 is an enlarged cross section view indicated in FIG. 2 by section line 8—8. The cross hatching indicates the contour with respect to the section line 8—8. The solid lines depict the straight protruding probe beam contour surfaces. The dashed lines illustrate the environmental structure of an exemplary buckling beam.

FIG. 9 is an enlarged cross section view indicated in FIG. 2 by section line 9—9. The cross hatching indicates the contour with respect to the section line 9—9. The solid lines depict the straight protruding probe beam contour surfaces. The dashed lines illustrate the environmental structure of an exemplary buckling beam; and,

FIG. 10 is an enlarged cross section view indicated in FIG. 2 by section line 10—10. The cross hatching indicates the contour with respect to the section line 10—10. The solid lines depict the straight protruding probe beam contour surfaces. The dashed lines illustrate the environmental structure of an exemplary buckling beam.

The broken lines shown in FIGS. 1–10 are for illustrative purposes only and form no part of the claimed design.

1 Claim, 3 Drawing Sheets



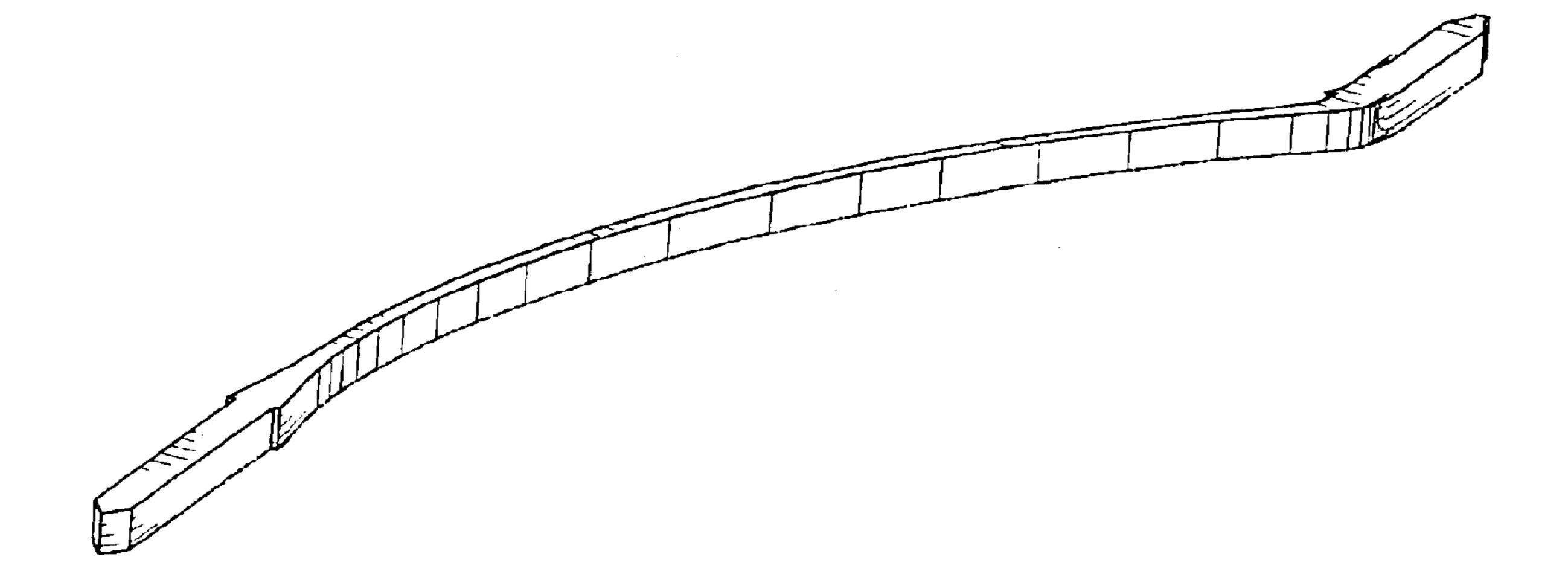


FIG. 1

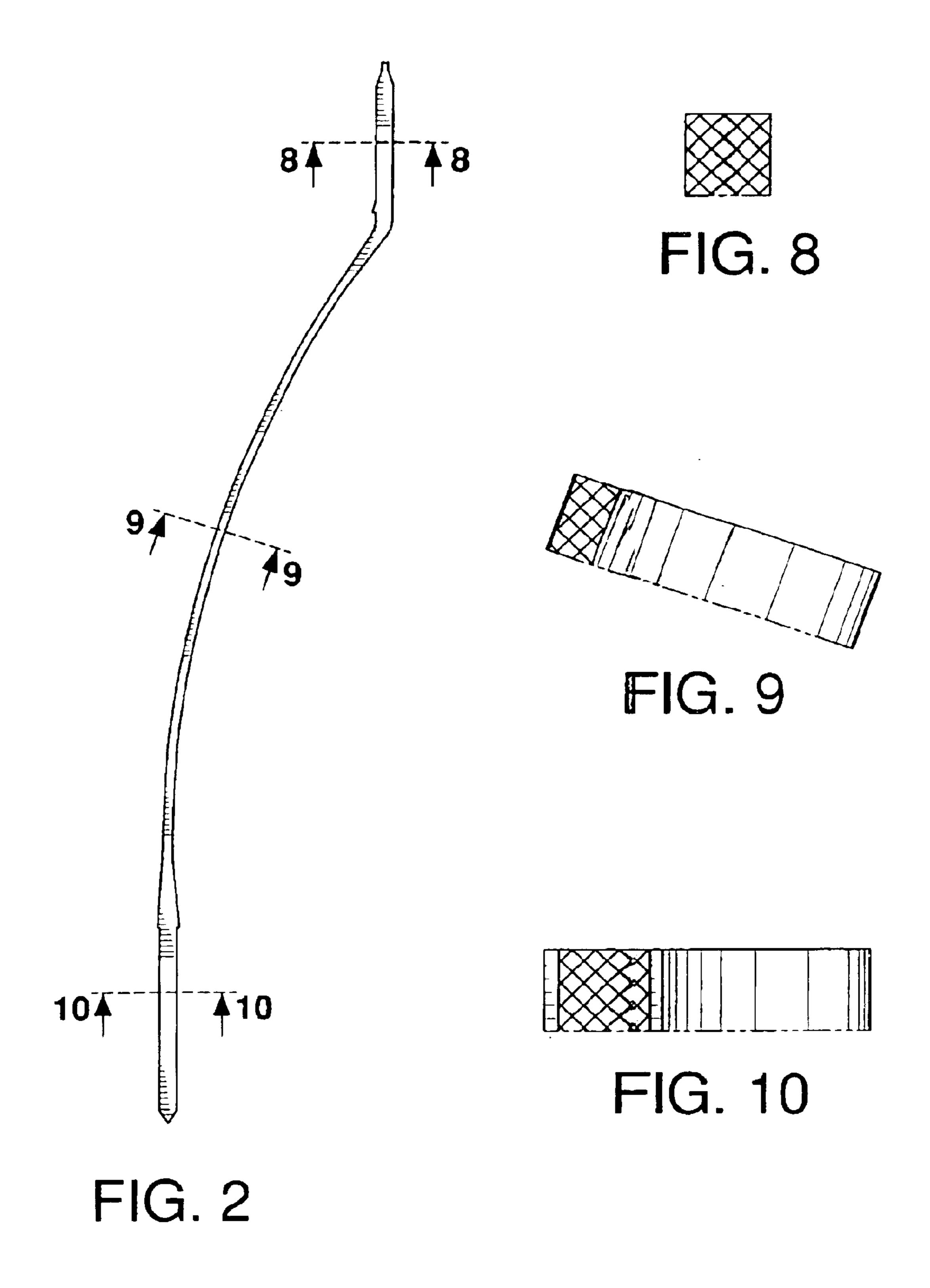


FIG. 4

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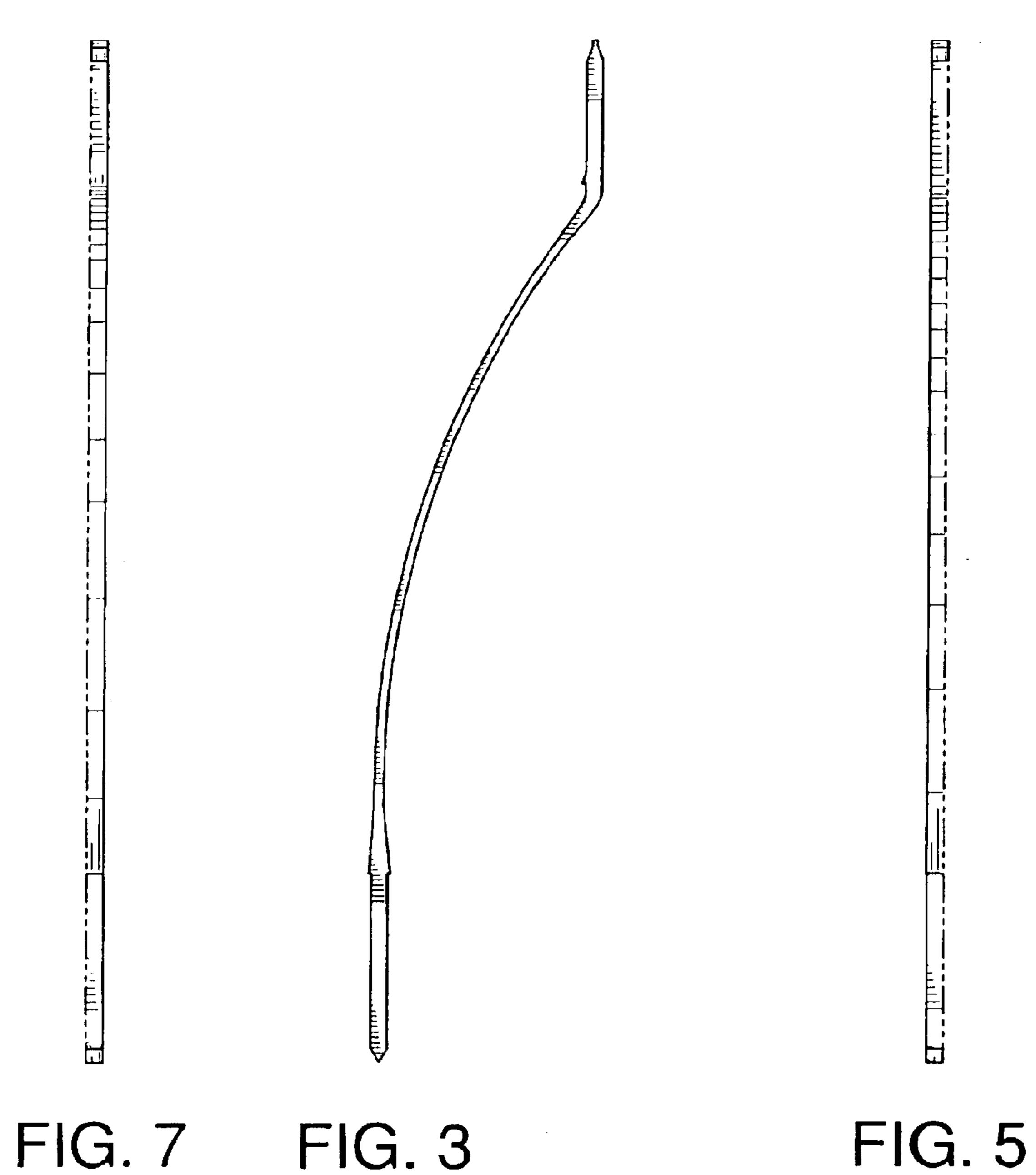


FIG. 6